L Number	Hits	Search Text	DB	Time stamp
1	3	365/189.09,189.11,230.06,201,226,190,203-2	DESPAT: 154	15260.0042/10:77/15
_		and (bias with generator) same SRAM same	US-PGPUB;	07:33
		test\$3	1	07.33
		cescas	EPO; JPO;	
			DERWENT;	
			IBM TDB	İ
2	22	365/189.09,189.11,230.06,201,226,190,203-2	DESPAT: 154.	1 5260.0b4b/10s7./15
		and (bias with generator) same SRAM	US-PGPUB;	0.7:35
<u> </u>		did (blas with generator) same siver		
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
3	20	(adjust\$3 with bias) same (test with	USPAT;	2004/07/15
		memory)	US-PGPUB;	07:36
•	İ		EPO; JPO;	07.30
				•
			DERWENT;	
			IBM TDB	
4	4	365/201.ccls. and (adjust\$3 with bias)	USPAT;	2004/07/15
		same (test with memory)	US-PGPUB;	07:37
		Same (cest with memory)	1	107.37
			EPO; JPO;	
	1		DERWENT;	
			IBM TDB	1
5	96	365/\$.cclsand_((pull-up_or_pull-down)-	-USPAT;	2004/07/15
	<u>-</u> -	with transistor) or (metal with	US-PGPUB;	07:39
				07.39
		program\$4)) and (adjust\$4 or level\$) and	EPO; JPO;	
		bias same voltage same test\$4 and (SRAM	DERWENT;	
		or (static with random with access	IBM TDB	
	1	memory))	_	
6	56	365/189.09,189.11,230.06,201,226,190,203-2	n Erenoun. 1E4	1 5727 0-1-10-7 /1 5
· ·	30			
		and (((pull-up or pull-down) with	US-PGPUB;	07:39
		transistor) or (metal with program\$4))	EPO; JPO;	
]	and (adjust\$4 or level\$) and bias same	DERWENT;	
	l	voltage same test\$4 and (SRAM or (static	IBM TDB	1
7	29	የ ይደመር የተመሰው የተመሰው የተመሰው የሚያ ነው። የመደመው የመ		1 520 04-10-7 / 1 5
′	2.5			
		and (((pull-up or pull-down) with	US-PGPUB;	07:39
		transistor) or (metal with program\$4))	EPO; JPO;	
		and (adjust\$4 or level\$) same bias same	DERWENT;	
		voltage same test\$4 and (SRAM or (static	IBM TDB	1
_	6	whitesrwindhmgwinehatoresanmlendam) and	USPAT;	2004/07/15
	١		1	
	ļ	(voltage with output with signal) and	US-PGPUB;	07:32
		(metal with program\$4)	EPO; JPO;	-
			DERWENT;	
			IBM TDB	
_	14	(bias with generator) and SRAM and	USPĀT;	2004/07/03
	13		1	
		voltage same output same signal and	US-PGPUB;	16:12
		(metal with program\$4)	EPO; JPO;	
			DERWENT;	I
			IBM TDB	
_	1	((Blaine with Stackhouse) and (Hewlett	USPAT;	2004/07/03
				1
		with packard with development with	US-PGPUB;	16:20
		company))	EPO; JPO;	
			DERWENT;	
			IBM TDB	
_	4	((Blaine with Stackhouse) or (Hewlett	USPAT;	2004/07/03
	· •	, ,	1	1 ' '
		with packard with development with	US-PGPUB;	16:22
		company)) and (bias with generator)	EPO; JPO;	
			DERWENT;	1
			IBM TDB	1
_	103	(/Blaine with Stackhouse) on /Herricht		2004/07/03
-	103		USPAT;	2004/07/03
		with packard with development with	US-PGPUB;	16:22
		company)) and 365/\$.ccls.	EPO; JPO;	
			DERWENT;	
			IBM TDB	
_	^7	//Plaine with Charles and ///		2004/07/00
-	27		USPĀT;	2004/07/03
		with packard with development with	US-PGPUB;	16:55
		company)) and 365/\$.ccls. and bias	EPO; JPO;	
		- ···	DERWENT;	
			IBM TDB	I

		//Plaine with Charlibana (II-1)	tranam	1 2 2 2 4 / 2 7 / 2 2
	10	((Blaine with Stackhouse) or (Hewlett with packard with development with company)) and 365/\$.ccls. and bias and	USPAT; US-PGPUB; EPO; JPO;	2004/07/03
	_	metal	DERWENT; IBM_TDB	
-	3	365/\$.ccls. and (bias with generator) same transistor same metal	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/07/03
			IBM_TDB	2004/07/02
	66	(bias with generator) same transistor same metal	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/07/03
-	1	(bias with generator) same transistor same metal same program\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/07/03
-	2	365/230.06,201,226,190,203-205,194,154,156 and (bias with generator) same transistor _same_metal	IBM_TDB .USPAT; US-PGPUB; -EPO;-JPO;-	2004/07/15
			DERWENT; IBM TDB	
-	12	program\$4 with bias with test\$4 and SRAM	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/07/06 18:01
-	3	((pull-up or pull-down) with transistor) same bias same test\$4 and SRAM	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/07/07 09:26
-	6	((pull adj up) or (pull adj down) with transistor) same bias came test\$4 and SRAM	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/07/06 18:05
	1.6	(((pull-up or pull-down) with transistor) or (metal with program\$4)) same (adjust\$4 or level\$) same bias same test\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/07/07 10:41
-	17	("4916668" "4967395" "5132575" "5245578" "5302870" "5369317" "55555523" "5677886" "5680344" "5701268" "5732033" "5862089" "5877993" "5912853" "5991216" "6052322" "6157586").PN.	USPAT	2004/07/07
-	4	•	USPAT	2004/07/07
-	3	(SRAM or (static with random with access with memory)) and adjust\$ same magnitude\$1 same bias same test\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/07/07
-	6	(SRAM or (static with random with access with memory)) and adjust\$ same magnitude\$1 same bias and test\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/07/07 09:52
-	35	365/230.06,201,226,190,203-205,194,154,156 and (SRAM or (static with random with access with memory)) and (adjust\$ or ((pull adj up) and (pull adj down) with transistor)) same magnitude\$1 and test\$3		2004/07/07 10:20

	_	16	365/230.06,201,226,190,203-205,194,154,156		2004/07/08
			<pre>and (adjust\$ or ((pull adj up) and (pull adj down) with transistor)) same</pre>	US-PGPUB; EPO; JPO;	11:21
			magnitude\$1 and test\$3 and (SRAM or	DERWENT;	
			(static with random with access with	IBM TDB	<u> </u>
	-	1	memø\$y¢¢landabda\$adjust\$ or ((pull adj	USPĀT;	2004/07/07
			<pre>up) and (pull adj down) with transistor))</pre>	US-PGPUB;	10:06
			same (magnitude\$1 with bias with voltage)	EPO; JPO;	
			and test\$3 and (SRAM or (static withrandom with access with memory))	DERWENT; IBM TDB	
	_	2	365/230.06,201,226,190,203-205,194,154,156		2004/07/07
		_,	and (SRAM or (static with random with	US-PGPUB;	10:21
			access with memory)) and (adjust\$ or	EPO; JPO;	
			((pull adj up) and (pull adj down) with	DERWENT;	
		17	transistor)) same magnitude\$1 and test\$3	IBM_TDB	0004/07/07
	-	17	4fid916668"with4867865" "5132575" "5245578" "5302870" "5369317"	USPAT	2004/07/07
			"5555523" "5677886" "5680344"		10:32
			"5701268" "5732033" "5862089"		
			"5877993" "5912853" "5991216"		
			"6052322" "6157586").PN.		
	-	14	(((pull-up or pull-down) with transistor)	USPAT;	2004/07/08
			or (metal_with_program\$4)) same -(adjust\$4- or level\$) same bias same test\$4 and	EPO; JPO;	11:01
	l		(SRAM or (static with random with access	DERWENT;	
			memory))	IBM TDB	
	-	2	(((pull-up or pull-down) with transistor)	USPĀT;	2004/07/07
			or (metal with program\$4)) same (adjust\$4	US-PGPUB;	12:09
			or level\$) same bias same test\$4 and	EPO; JPO;	
			(SRAM or (static with random with access memory)) and weak	DERWENT; IBM TDB	
	_	14	(((pull-up or pull-down) with transistor)	USPAT;	2004/07/08
		•	or (metal with program\$4)) same (adjust\$4	US-PGPUB;	10:12
			or level\$) same bias same voltage same	EPO; JPO;	
			test\$4 and (SRAM or (static with random	DERWENT;	
		4	with access memory))	IBM_TDB USPAT;	2004/07/08
	-	7	(bias with generator) and (((pull-up or pull-down) with transistor) or (metal	US-PGPUB;	10:13
			with program\$4)) same (adjust\$4 or	EPO; JPO;	10.13
			level\$) same bias same voltage same	DERWENT;	
		-	test\$4 and (SRAM or (static with random	IBM_TDB	- '
		0.0	with access memory))	TIG D D III .	2004/07/00
	-	96	365/\$.ccls. and (((pull-up or pull-down) with transistor) or (metal with	USPAT; US-PGPUB;	2004/07/08 11:16
			program\$4)) and (adjust\$4 or level\$) and	EPO; JPO;	11.10
			bias same voltage same test\$4 and (SRAM	DERWENT;	
			or (static with random with access	IBM_TDB	
		227	memory))	TICDAM.	2004/07/00
	-	227	365/\$.ccls. and (((pull-up or pull-down) with transistor) or (metal with	USPAT; US-PGPUB;	2004/07/08 11:17
			program\$4)) and (adjust\$4 or level\$) and	EPO; JPO;	11.1/
			(bias with voltage) and test\$4 and (SRAM	DERWENT;	
	İ		or (static with random with access	IBM_TDB	
	ļ	3.5	memory))	******	0004/07/00
	-	16	365/\$.ccls. and (((pull-up or pull-down)	USPAT;	2004/07/08
	1		<pre>with transistor) or (metal with program\$4)) and (adjust\$4 or level\$) and</pre>	US-PGPUB; EPO; JPO;	10:41
			(bias with voltage with output with	DERWENT;	
			signal) and test\$4 and (SRAM or (static	IBM_TDB	
		1	with random with access memory))	_	
	-	35	365/230.06,201,226,190,203-205,194,154,156	· '	2004/07/08
			<pre>and (adjust\$ or ((pull adj up) and (pull adj down) with transistor)) same</pre>	US-PGPUB; . EPO; JPO;	11:24
			magnitude\$1 and test\$3 and (SRAM or	DERWENT;	
			(static with random with access with	IBM TDB	
	-	11	nbmesywith generator) and SRAM and	USPĀT;	2004/07/08
			adjust\$3 with magnitude	US-PGPUB;	10:54
				EPO; JPO;	
				DERWENT; IBM TDB	
L	 .		The state of the s	םחד ייחד	L

-	69	(((pull-up or pull-down) with transistor)	USPAT;	2004/07/08
		or program\$4) same (adjust\$4 or chang\$3)	US-PGPUB;	12:48
		same bias same voltage\$1 same test\$4 and	EPO; JPO;	i i
		(SRAM or (static with random with access memory))	DERWENT; IBM TDB	
_	19	365/\$.ccls. and (((pull-up or pull-down)	USPAT;	2004/07/08
		with transistor) or program\$4) same	US-PGPUB;	11:10
		(adjust\$4 or chang\$3) same bias same	EPO; JPO;	
		voltage\$1 same test\$4 and (SRAM or	_DERWENT;	
 · <u> </u>		(static with random with access memory))	IBM_TDB	
-	21	365/\$.ccls. and (((pull-up or pull-down)	USPAT;	2004/07/08
		with transistor) or program\$4) same	US-PGPUB;	11:12
		<pre>(adjust\$4 or chang\$3 or modif\$7) same bias same voltage\$1 same test\$4 and (SRAM)</pre>	EPO; JPO; DERWENT;	
		or (static with random with access	IBM_TDB	
		memory))		
_	4	365/\$.ccls. and (((pull-up or pull-down)	USPAT;	2004/07/08
		with transistor) or program\$4) same	US-PGPUB;	11:12
		(adjust\$4 or chang\$3 or modif\$7) same	EPO; JPO;	
		bias same voltage\$1 same test\$4 and (SRAM	DERWENT;	
		or (static adj random adj access adj	IBM_TDB	
_	57	<pre>memory)) (program\$4 and bias and test\$4 and SRAM)</pre>	_USPAT-;	_2004/07/08
 		aND (365/\$.ccls. and (((pull-up or	US-PGPUB;	11:20
İ		pull-down) with transistor) or (metal	EPO; JPO;	
ĺ		<pre>with program\$4)) and (adjust\$4 or level\$)</pre>	DERWENT;	
		and (bias with voltage) and test\$4 and	IBM_TDB	
		(SRAM or (static adj random adj access		
		memory)))	TYO D. M.	2024/07/20
-	1	365/230.06,201,226,190,203-205,194,154,156	. OSPAT; US-PGPUB;	2004/07/08 11:23
		<pre>and (adjust\$ OR CHANG\$3 or modif\$7 or ((pull adj up) and (pull adj down) with</pre>	EPO; JPO;	11.23
		transistor)) same magnitude\$1 same bias	DERWENT;	
		same voltage and test\$3 and (SRAM or	IBM TDB	
		(static adj random adj access adj	_	
-	34	nemørgp) 0en20bj226, 190, 203-205, 194, 154, 156		2004/07/08
		and (adjust\$ or ((pull adj up) and (pull	US-PGPUB;	11:28
		adj down) with transistor)) same	EPO; JPO;	
		magnitude\$1 and test\$3 and (SRAM or (static adj random adj access adj	DERWENT; IBM TDB	
_	4	memoryram\$4 and bias and test\$4 and SRAM)	USPĀT;	2004/07/08
 		aND (365/\$.ccls. and (((pull-up or	US-PGPUB;	11:24
		pull-down) with transistor) or (metal	EPO; JPO;	
		<pre>with program\$4)) and (adjust\$4 or level\$)</pre>	DERWENT;	
		and (bias with voltage) and test\$4 and	IBM_TDB	
		(SRAM or (static adj random adj access		
		memory)))) and (365/230.06,201,226,190,203-205,194,154,15	h.ccls	
		and (adjust\$ or ((pull adj up) and (pull	[
		adj down) with transistor)) same		
		magnitude\$1 and test\$3 and (SRAM or		
-	69	3654230.86j20anaam, aeg, acce285ad94, 154, 156		2004/07/08
		mando(sqd)just\$ or chang\$3 or modif\$7 or	US-PGPUB;	11:29
		<pre>((pull adj up) and (pull adj down) with transistor)) same magnitude\$1 and test\$3</pre>	EPO; JPO; DERWENT;	
		and (SRAM or (static adj random adj	IBM TDB	
_	1	and (Skar of (Static ad) fandom ad) a66e230ad6, 200mo226) 190, 203-205, 194, 154, 156		2004/07/08
	_	and (adjust\$ or chang\$3 or modif\$7 or	US-PGPUB;	11:30
		((pull adj up) and (pull adj down) with	EPO; JPO;	
		transistor)) same magnitude\$1 same bias	DERWENT;	
		same voltage and test\$3 and (SRAM or	IBM_TDB	
	ر ا	(static adj random adj access adj mandopnyt\$ or chang\$3 or modif\$7) same	USPAT;	2004/07/08
		((pull adj up) and (pull adj down) with	US-PGPUB;	11:34
		transistor) same bias same voltage and	EPO; JPO;	
]	(test\$3 with (SRAM or (static adj random	DERWENT;	
		adj access adj memory)))	IBM_TDB	
_	5	(((pull-up or pull-down) with transistor)	USPAT;	2004/07/08
		or program\$4) same (supply with voltage)	US-PGPUB;	12:53
		same (bias with generator) same output and test\$4 and (SRAM or (static with	EPO; JPO; DERWENT;]
		random with access memory))	IBM TDB	
L	1		1	ł <u></u>